

Dual P-channel Enhancement Mode Power MOSFET

Features

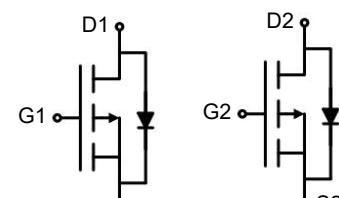
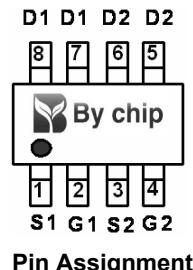
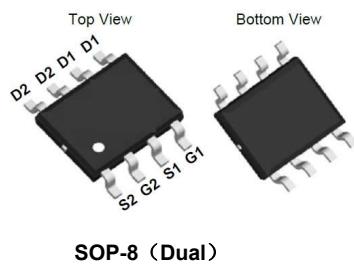
- $V_{DS} = -20V$, $I_D = -13 A$
- $R_{DS(ON)} < 15m\Omega$ @ $V_{GS} = -10V$
- $R_{DS(ON)} < 20m\Omega$ @ $V_{GS} = -4.5V$

General Features

- Advanced Trench Technology
- Provide Excellent $R_{DS(ON)}$ and Low Gate Charge
- Lead Free and Green Available

100% UIS TESTED!

100% ΔV_{ds} TESTED!



Maximum ratings, at $T_A = 25^\circ C$, unless otherwise specified

Symbol	Parameter	Rating	Unit
$V(BR)DSS$	Drain-Source breakdown voltage	-20	V
V_{GS}	Gate-Source voltage	± 12	V
I_S	Diode continuous forward current	$T_A = 25^\circ C$	A
I_D	Continuous drain current@ $V_{GS}=-4.5V$	$T_A = 25^\circ C$	A
		$T_A = 70^\circ C$	A
I_{DM}	Pulse drain current tested ①	$T_A = 25^\circ C$	A
EAS	Avalanche energy, single pulsed ②	42	mJ
P_D	Maximum power dissipation	$T_A = 25^\circ C$	W
$T_{STG,TJ}$	Storage and operating temperature range	-55 to 150	°C

Thermal Characteristics

Symbol	Parameter	Typical	Max	Unit
$R_{\theta JL}$	Thermal Resistance-Junction to Lead		29	°C/W
$R_{\theta JA}$	Thermal Resistance-Junction to Ambient		48	°C/W

Electrical Characteristics

Symbol	Parameter	Condition	Min.	Typ.	Max.	Unit
Static Electrical Characteristics @ $T_j = 25^\circ\text{C}$ (unless otherwise stated)						
V(BR)DSS	Drain-Source Breakdown Voltage	$V_{GS}=0\text{V}, I_D=-250\mu\text{A}$	-20	--	--	V
IDSS	Zero Gate Voltage Drain Current	$V_{DS}=-20\text{V}, V_{GS}=0\text{V}$	--	--	-1	μA
	Zero Gate Voltage Drain Current($T_j=125^\circ\text{C}$)	$V_{DS}=-20\text{V}, V_{GS}=0\text{V}$	--	--	-100	μA
IGSS	Gate-Body Leakage Current	$V_{GS}=\pm 12\text{V}, V_{DS}=0\text{V}$	--	--	± 100	nA
VGS(th)	Gate Threshold Voltage	$V_{DS}=V_{GS}, I_D=-250\mu\text{A}$	-0.3		-2.0	V
RDS(on)	Drain-Source On-State Resistance ③	$V_{GS}=-4.5\text{V}, I_D=-10\text{A}$	--		15	$\text{m}\Omega$
RDS(on)	Drain-Source On-State Resistance ③	$V_{GS}=-2.5\text{V}, I_D=-10\text{A}$	--		20	$\text{m}\Omega$
RDS(on)	Drain-Source On-State Resistance ③	$V_{GS}=-1.8\text{V}, I_D=-8\text{A}$	--		32	$\text{m}\Omega$
Dynamic Electrical Characteristics @ $T_j = 25^\circ\text{C}$ (unless otherwise stated)						
Ciss	Input Capacitance	$V_{DS}=-10\text{V}, V_{GS}=0\text{V}, f=1\text{MHz}$			4655	pF
Coss	Output Capacitance				465	pF
Crss	Reverse Transfer Capacitance				335	pF
Rg	Gate Resistance	f=1MHz	0.2		5	Ω
Qg	Total Gate Charge	$V_{DS}=-10\text{V}, I_D=-10\text{A}, V_{GS}=-4.5\text{V}$	--		39	nC
Qgs	Gate-Source Charge		--		8.1	nC
Qgd	Gate-Drain Charge		--		7.8	nC
Switching Characteristics						
Td(on)	Turn-on Delay Time	$V_{DD}=-10\text{V}, I_D=-10\text{A}, R_G=2.7\Omega, V_{GS}=-10\text{V}$	--	7.6	--	ns
Tr	Turn-on Rise Time		--	44	--	ns
Td(off)	Turn-Off Delay Time		--	75	--	ns
Tf	Turn-Off Fall Time		--	27	--	ns
Source- Drain Diode Characteristics@ $T_j = 25^\circ\text{C}$ (unless otherwise stated)						
VSD	Forward on voltage	$I_{SD}=-10\text{A}, V_{GS}=0\text{V}$	--	-0.8	-1.2	V
Trr	Reverse Recovery Time	$T_j=25^\circ\text{C}, I_{sd}=-10\text{A}, V_{GS}=0\text{V}$ $dI/dt=-100\text{A}/\mu\text{s}$	--	14	28	ns
Qrr	Reverse Recovery Charge		--	4.7	9.4	nC

NOTE:

- ① Repetitive rating; pulse width limited by max junction temperature.
- ② Limited by T_{Jmax} , starting $T_J = 25^\circ\text{C}$, $L = 0.5\text{mH}$, $R_G = 25\Omega$, $I_{AS} = -13\text{A}$, $V_{GS} = -10\text{V}$. Part not recommended for use above this value
- ③ Pulse width $\leq 380\mu\text{s}$; duty cycle $\leq 2\%$.

Typical Characteristics

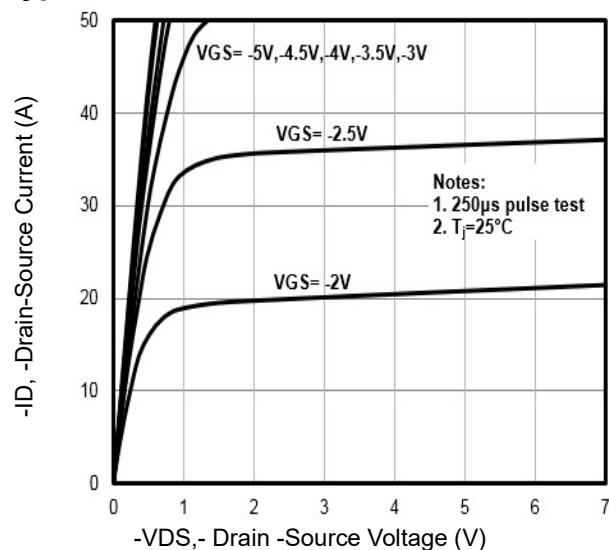


Fig1. Typical Output Characteristics

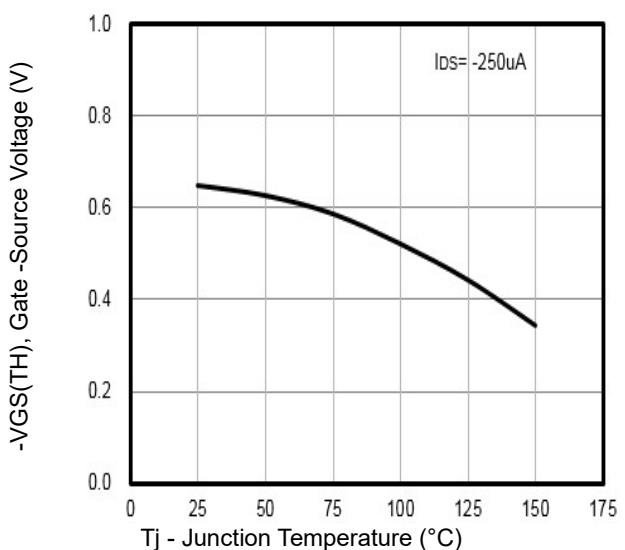


Fig2. $-VGS(TH)$ Gate-Source Voltage Vs. T_j

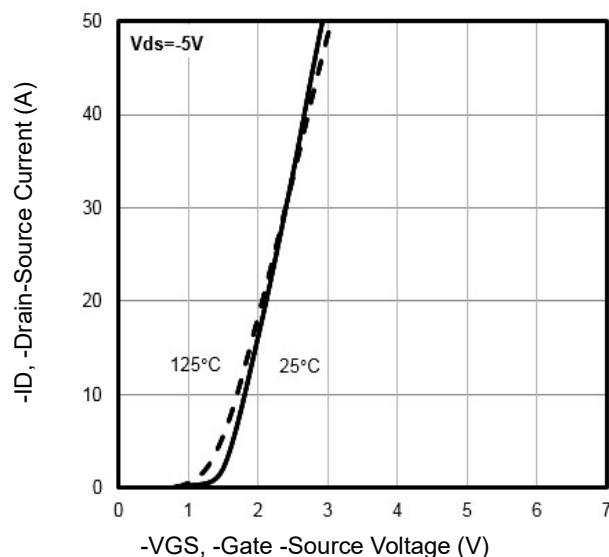


Fig3. Typical Transfer Characteristics

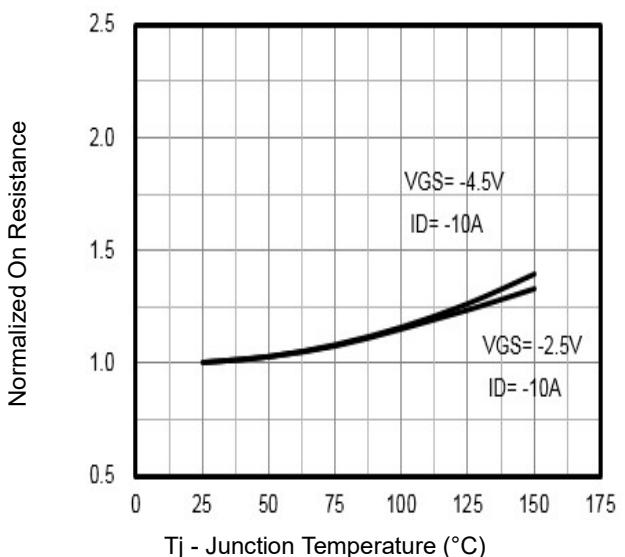


Fig4. Normalized On-Resistance Vs. T_j

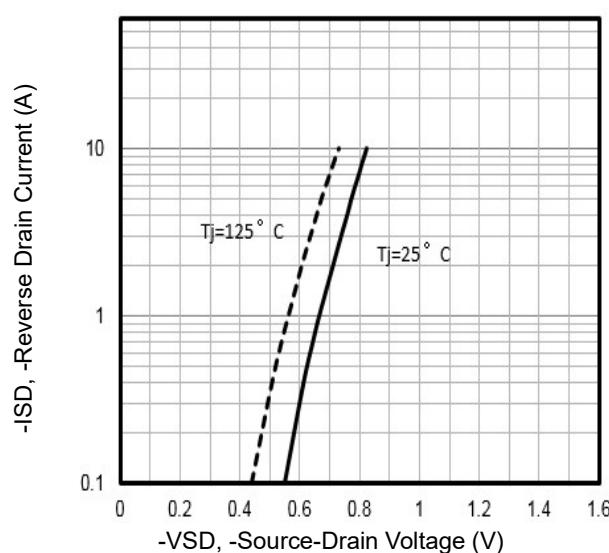


Fig5. Typical Source-Drain Diode Forward Voltage

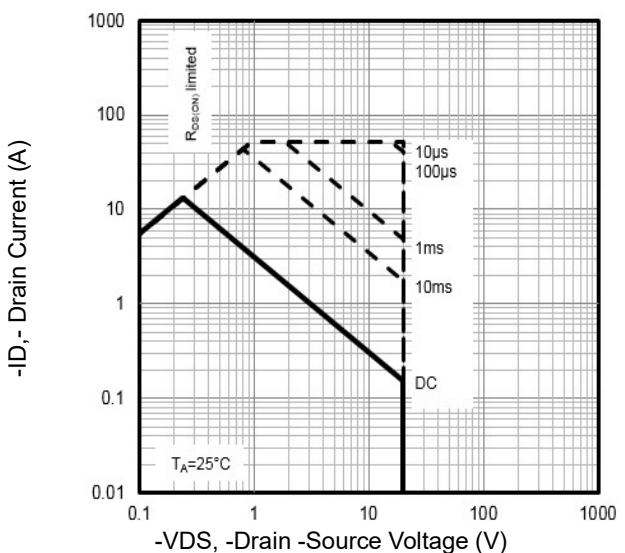


Fig6. Maximum Safe Operating Area

Typical Characteristics

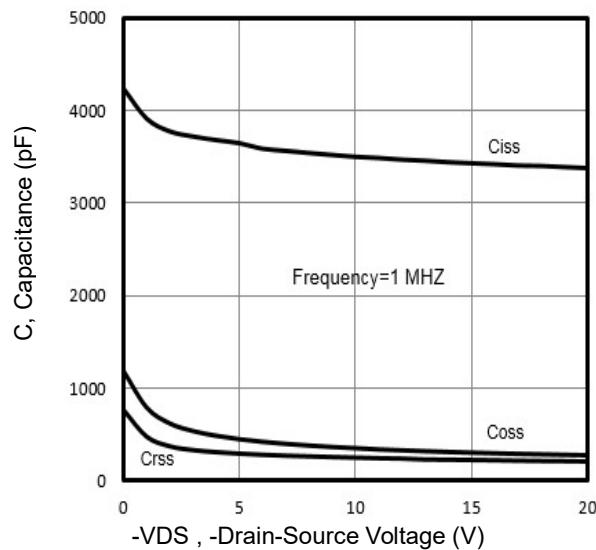


Fig7. Typical Capacitance Vs.Drain-Source Voltage

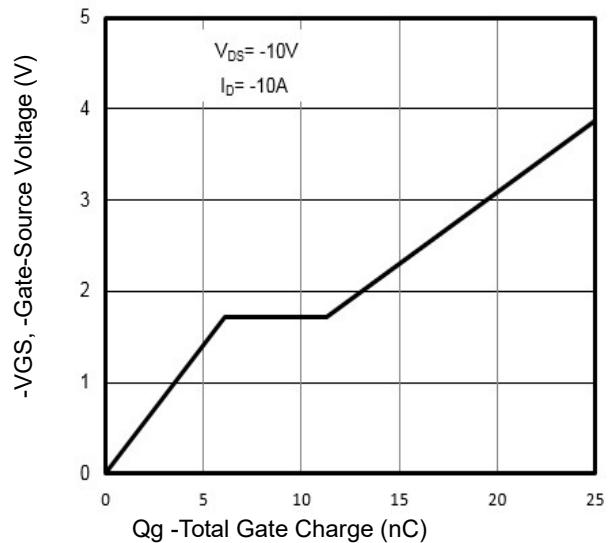


Fig8. Typical Gate Charge Vs.Gate-Source Voltage

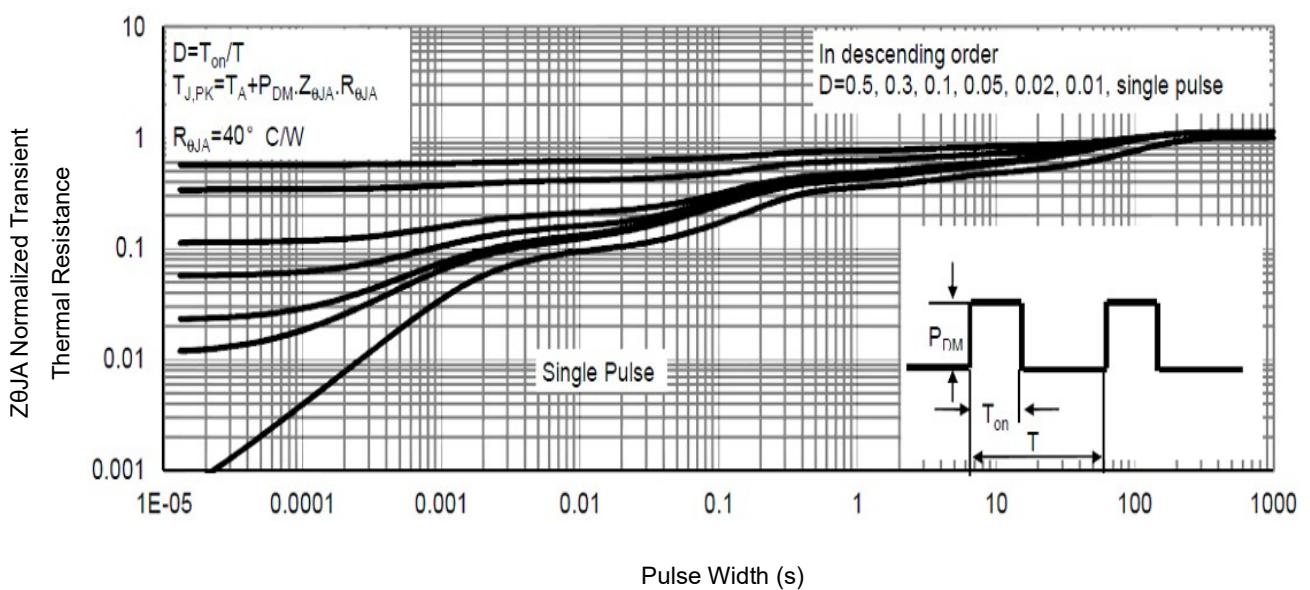


Fig9. Normalized Maximum Transient Thermal Impedance

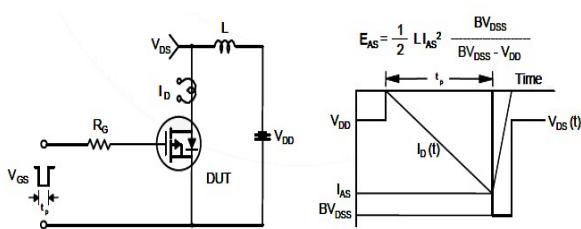


Fig10. Unclamped Inductive Test Circuit and Waveforms

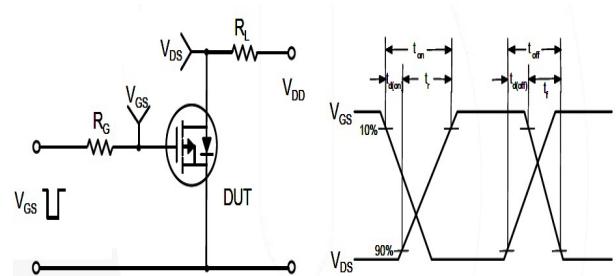


Fig11. Switching Time Test Circuit and waveforms